**Product data sheet** 

### 1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a IITO220 plastic package intended for use in applications requiring very high inrush current capability, high thermal cycling performance and high junction temperature capability ( $T_{j(max)} = 150$  °C).

### 2. Features and benefits

- · AC power control
- · High blocking voltage capability
- · High thermal cycling performance
- · Planar passivated for voltage ruggedness and reliability
- · High immunity to false turn-on by dV/dt
- Internally insulated package
- · Internally isolated mounting base
- High junction operating temperature capability (T<sub>i(max)</sub> = 150 °C)
- Package meets UL94V0 flammability requirement
- · Package is RoHS compliant
- · IEC 61000-4-4 fast transient

### 3. Applications

- Capacitive Discharge Ignition (CDI)
- Crowbar protection
- Inrush protection
- Motor control
- · Voltage regulation

### 4. Quick reference data

### Table 1. Quick reference data

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		800	V
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; $T_{mb} \le 114 ^{\circ}\text{C}$ ; Fig. 1; Fig. 2; Fig. 3	30	А
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 10 ms; Fig 4; Fig 5	350	А
		half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 8.3 ms	385	Α
T <sub>j</sub>	junction temperature		150	°C

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Static ch	Static characteristics						
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$		6	-	15	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>		-	-	60	mA
V <sub>T</sub>	on-state voltage	I <sub>T</sub> = 60 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>		-	1.3	1.5	V
Dynamic	Dynamic characteristics						
dV <sub>D</sub> /dt	rate of rise of off-state voltage	V <sub>DM</sub> = 402 V; T <sub>j</sub> = 150 °C; exponential waveform; gate open circuit		1000	-	-	V/µs

# 5. Pinning information

### **Table 2. Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode		A N. 17
2	А	anode		A   K G
3	G	gate		sym037
mb	n.c.	mounting base; isolated	IITO-220 1 2 3 E P	

# 6. Ordering information

### **Table 3. Ordering information**

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
TYN30Y-800T	IITO220	TYN30Y-800TQ	Tube	50	IITO220E (E)	15-Dec-2017
					IITO220P (P)	31-Mar-2023

# 7. Marking

### Table 4. Marking codes

Type number	Marking codes		
	Assembly factory: E	Assembly factory: P	
TYN30Y-800T	TYN30Y 800T PJExxxx xx	TYN30Y 800T PJPxxxx xx	

# 8. Limiting values

#### **Table 5. Limiting values**

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Values	Unit
$V_{DRM}$	repetitive peak off-state voltage		800	V
$V_{RRM}$	repetitive peak reverse voltage		800	V
I <sub>T(AV)</sub>	average on-state current	half sine wave; T <sub>mb</sub> ≤ 114 °C;	19	А
I <sub>T(RMS)</sub>	RMS on-state current	half sine wave; T <sub>mb</sub> ≤ 114 °C; Fig. 1; Fig. 2; Fig. 3	30	А
I <sub>TSM</sub>	non-repetitive peak on- state current	half sine wave; $T_{j(init)}$ = 25 °C; $t_p$ = 10 ms; Fig 4; Fig 5	350	А
		half sine wave; $T_{j(init)} = 25 \text{ °C}$ ; $t_p = 8.3 \text{ ms}$	385	А
I <sup>2</sup> t	I <sup>2</sup> t for fusing	t <sub>p</sub> = 10 ms; sine-wave pulse	612.5	A <sup>2</sup> s
dl <sub>⊤</sub> /dt	rate of rise of on-state current	I <sub>G</sub> = 30 mA	200	A/µs
I <sub>GM</sub>	peak gate current		5	А
$V_{RGM}$	peak reverse gate voltage		5	V
$P_{GM}$	peak gate power		20	W
$P_{G(AV)}$	average gate power	over any 20 ms period	0.5	W
T <sub>stg</sub>	storage temperature		-40 to 150	°C
T <sub>j</sub>	junction temperature		150	°C

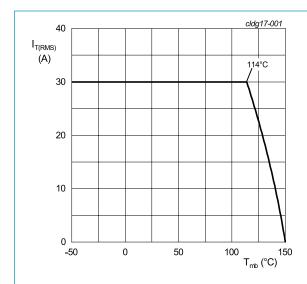
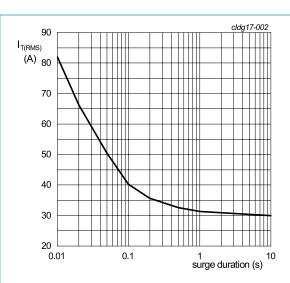
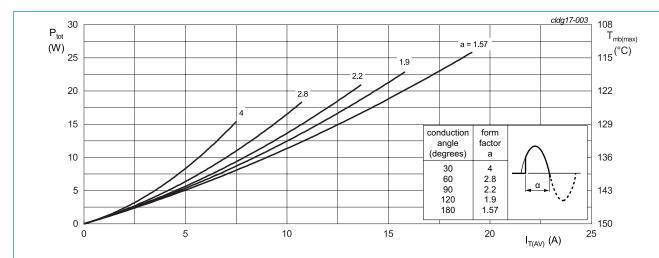


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values

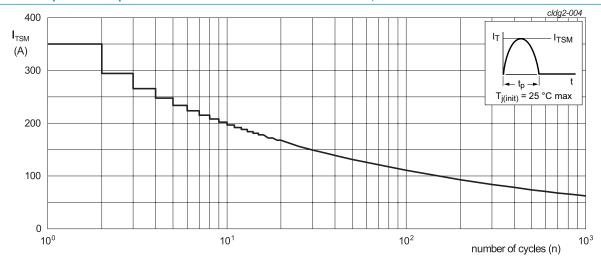


f = 50 Hz; T<sub>mb</sub> = 114 °C Fig. 2. RMS on-state current as a function of surge duration; maximum values



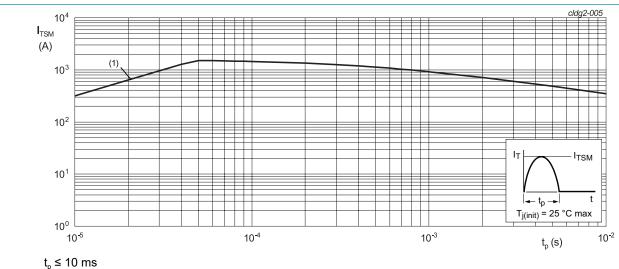
 $\alpha$  = conduction angle

 $a = form \ factor = I_{T(RMS)}/I_{T(AV)}$  Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values



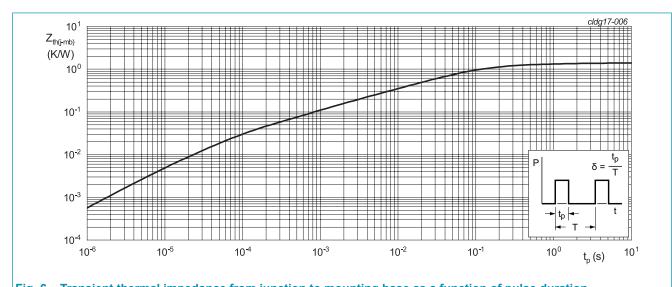
(1) dl<sub>⊤</sub>/dt limit

Non-repetitive peak on-state current as a function of pulse duration; maximum values Fig. 5.

### 9. Thermal characteristics

### **Table 6. Thermal characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-mb)}}$	thermal resistance from junction to mounting base	Fig 6	-	-	1.4	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	in free air	-	60	-	K/W



### Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

### 10. Isolation characteristics

**Table 7. Isolation characteristics** 

Symb	ol Parameter	Conditions	Min	Тур	Max	Unit
V <sub>isol(RMS</sub>	RMS isolation voltage	50 Hz ≤ f ≤ 60 Hz; RH ≤ 65 %; from all pins to external heatsink; sinusoidal waveform; clean and dust free	-	-	2500	V
$C_{isol}$	isolation capacitance	from cathode to external heatsink	-	10	-	pF

### 11. Characteristics

**Table 8. Characteristics** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static ch	naracteristics					
I <sub>GT</sub>	gate trigger current	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 7$	6	-	15	mA
IL	latching current	$V_D = 12 \text{ V}; I_G = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 8$	-	-	80	mA
I <sub>H</sub>	holding current	V <sub>D</sub> = 12 V; T <sub>j</sub> = 25 °C; <u>Fig. 9</u>	-	-	60	mA
$V_T$	on-state voltage	I <sub>T</sub> = 60 A; T <sub>j</sub> = 25 °C; <u>Fig. 10</u>	-	1.3	1.5	V
$V_{GT}$	gate trigger voltage	$V_D = 12 \text{ V}; I_T = 0.1 \text{ A}; T_j = 25 \text{ °C}; Fig. 11$	-	0.6	1	V
		V <sub>D</sub> = 400 V; I <sub>T</sub> = 0.1 A;T <sub>j</sub> = 125 °C	0.25	0.4	-	V
I <sub>D</sub>	off-state current	V <sub>D</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>D</sub> = 800 V; T <sub>j</sub> = 150 °C	-	-	1	mA
I <sub>R</sub>	reverse current	V <sub>R</sub> = 800 V; T <sub>j</sub> = 25 °C	-	-	10	μA
		V <sub>R</sub> = 800 V; T <sub>j</sub> = 150 °C	-	-	1	mA
Dynamic	characteristics			•		•
dV <sub>D</sub> /dt	rate of rise of off-state voltage	$V_{DM}$ = 402 V; $T_j$ = 150 °C; exponential waveform; gate open circuit	1000	-	-	V/µs
		$V_{DM}$ = 536 V; $T_j$ = 150 °C; ( $V_{DM}$ = 67% of $V_{DRM}$ ); exponential waveform; gate open circuit	500	-	-	V/µs
t <sub>gt</sub>	gate-controlled turn-on time	$I_{TM} = 30 \text{ A}; V_D = 800 \text{ V}; I_G = 100 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$	-	2	-	μs
t <sub>d</sub>	turn-on delay	$I_{TM} = 30 \text{ A}; V_D = 800 \text{ V}; I_G = 100 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$	-	1	-	μs
t <sub>r</sub>	rise time	$I_{TM} = 30 \text{ A}; V_D = 800 \text{ V}; I_G = 100 \text{ mA};$ $dI_G/dt = 5 \text{ A}/\mu\text{s}; T_j = 25 ^{\circ}\text{C}$	-	1	-	μs
t <sub>q</sub>	commutated turn-off time	$V_{DM}$ = 536 V; $T_j$ = 150 °C; $I_{TM}$ = 30 A; $V_R$ = 25 V; $dI_T/dt$ = 30 A/ $\mu$ s; $dV_D/dt$ = 50 V/ $\mu$ s	-	70	-	μs

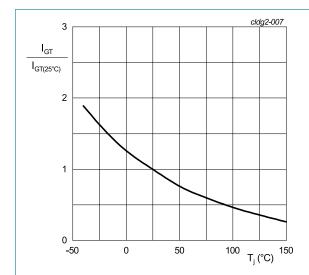


Fig. 7. Normalized gate trigger current as a function of junction temperature

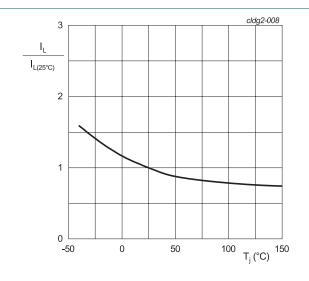


Fig. 8. Normalized latching current as a function of junction temperature

TYN30Y-800T

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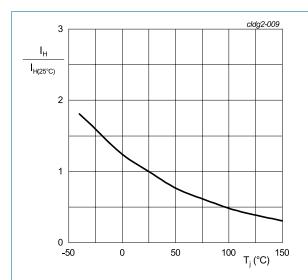
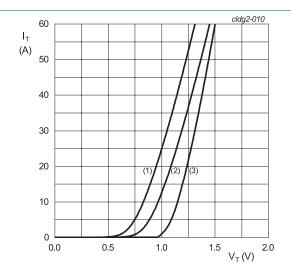


Fig. 9. Normalized holding current as a function of junction temperature



 $V_o$  = 0.899 V;  $R_s$  = 0.0096 Ω (1)  $T_j$  = 150 °C; typical values (2)  $T_j$  = 150 °C; maximum values (3)  $T_j$  = 25 °C; maximum values

Fig. 10. On-state current as a function of on-state voltage

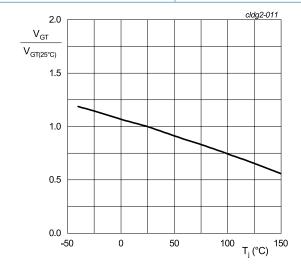
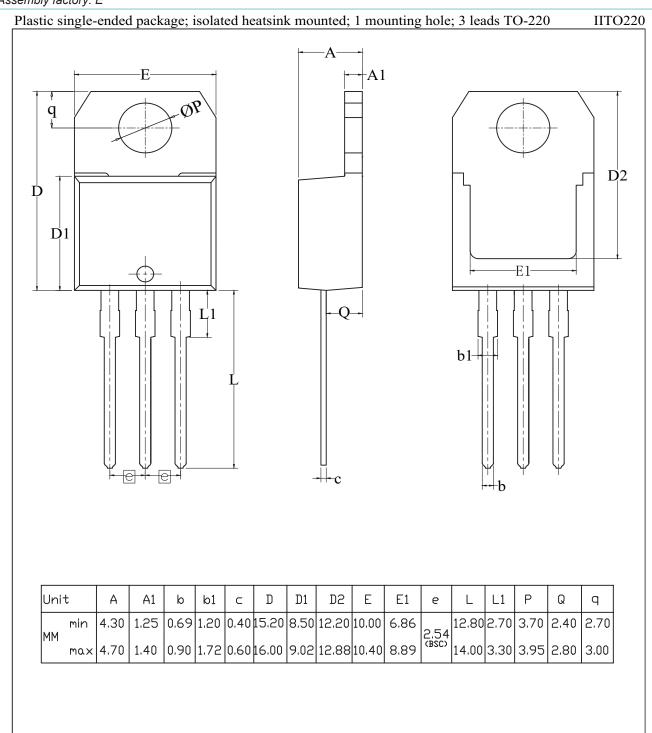
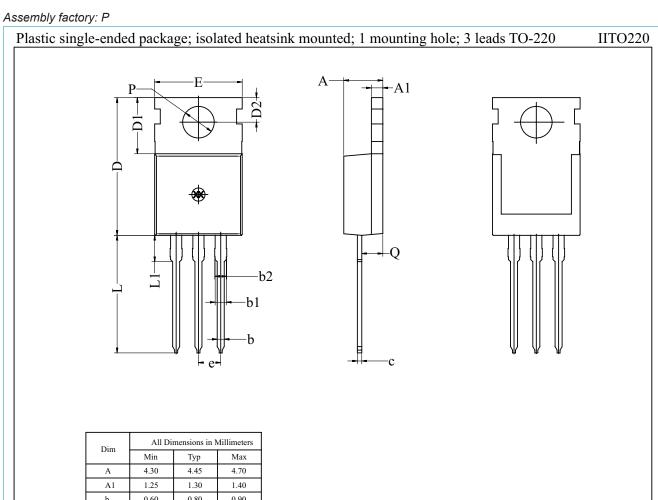


Fig. 11. Normalized gate trigger voltage as a function of junction temperature

# 12. Package outline

Assembly factory: E





Dim	All Dimensions in Millimeters			
Dilli	Min	Тур	Max	
A	4.30	4.45	4.70	
A1	1.25	1.30	1.40	
ь	0.60	0.80	0.90	
b1	1.10	1.27	1.40	
b2	1.32	1.37	1.72	
с	0.40	0.50	0.60	
D	15.20	15.70	16.00	
D1	6.20	6.40	6.60	
D2	2.70	2.80	3.00	
Е	9.70	10.00	10.30	
e		2.54 BSC		
L	12.80	13.40	14.00	
L1	2.80	3.00	3.20	
P	3.50	3.60	3.70	
0	2.20	2.40	2.60	

### 13. Legal information

#### Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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